

Parameter extraction issues in HICUM / L2 for very advanced HBTs

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Outline

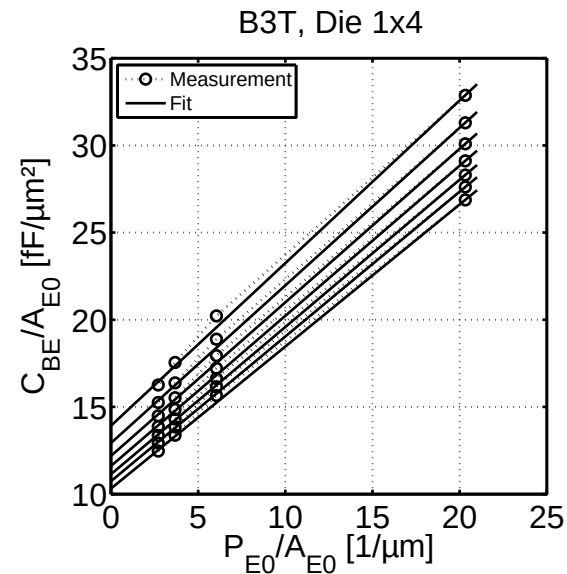
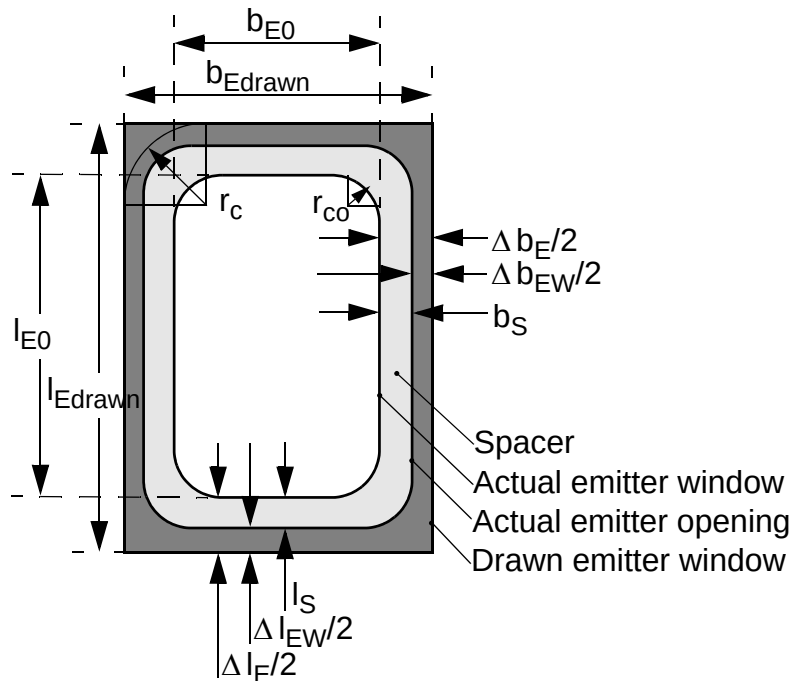
- Introduction
- Extraction issues without regard to model formulation
- Extraction issues with regard to model formulation
- Model comparison
- Summary

1 Introduction

- Observation of model limitations for very advanced HBTs
- Database: ST B3T technology (HBTs with $f_{\max} > 0.3\text{THz}$), developed within the DOTFIVE project (<http://www.dot-five.eu>)
- Very aggressive device performance, SiGe HBT structure extremely scaled down laterally and vertically, striking self-heating effect
- Extracted models show partially accuracy issues
- Solving some extraction issues makes changes/extensions to certain model formulations inevitable

2 Extraction issues w/o regard to model formulation

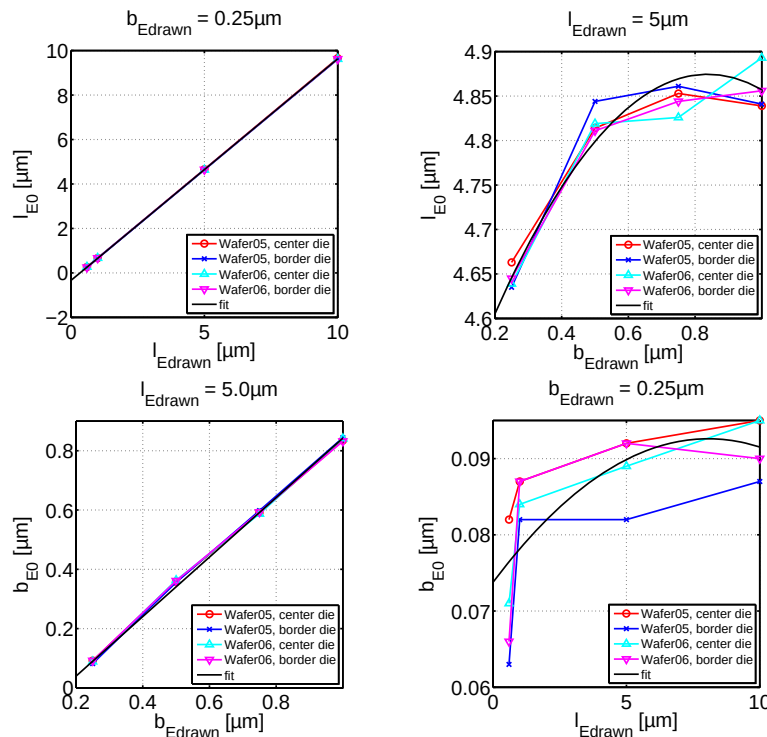
Influence of exact emitter dimensions on scalability



P/A separation of
BE capacitance

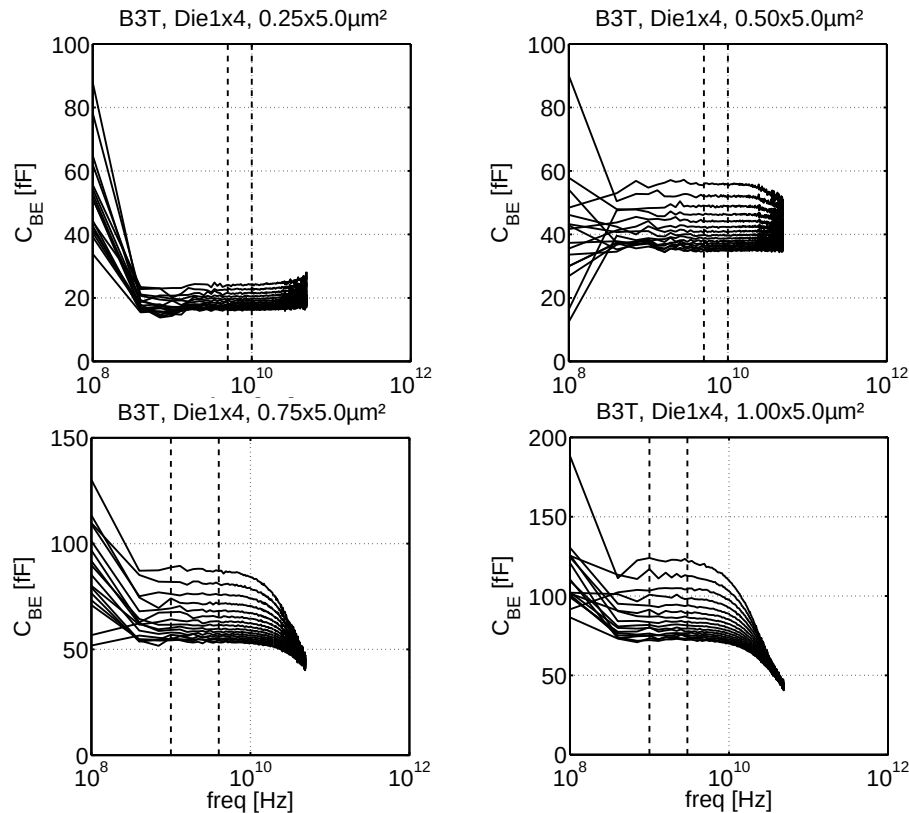
2 Extraction issues w/o regard to model formulation (1)

Analyses across various die sites (based on SEM data)



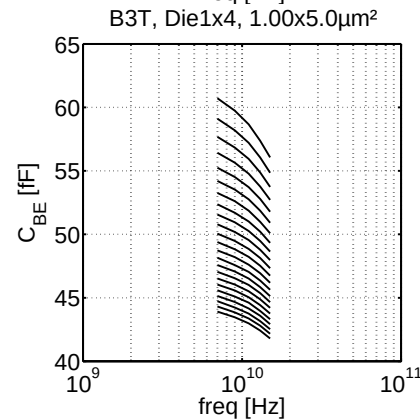
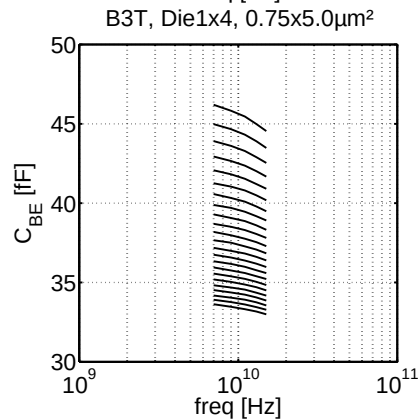
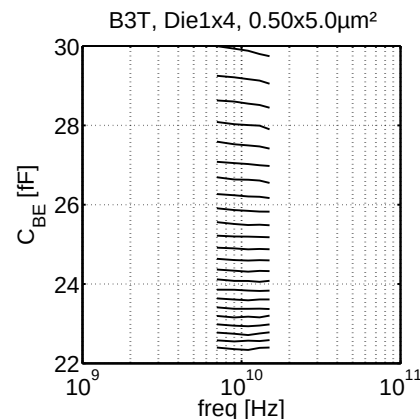
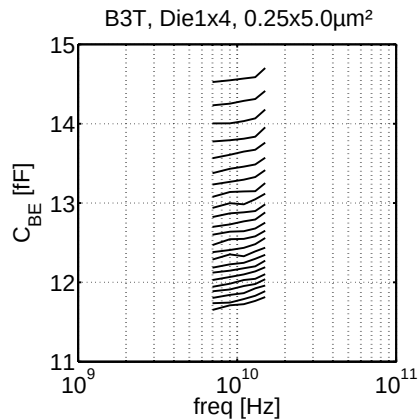
- Information on actual emitter dimensions derived from SEM pictures provided by ST
- Transformation from drawn width and length to actual dimensions using a second-order model

2 Extraction issues w/o regard to model formulation (2)



- TUD data
- C_{BE} vs. frequency
- $V_{BE} = (0.65 \dots 0.8) \text{V}$
- Measurements at spot frequency are obviously not sufficient

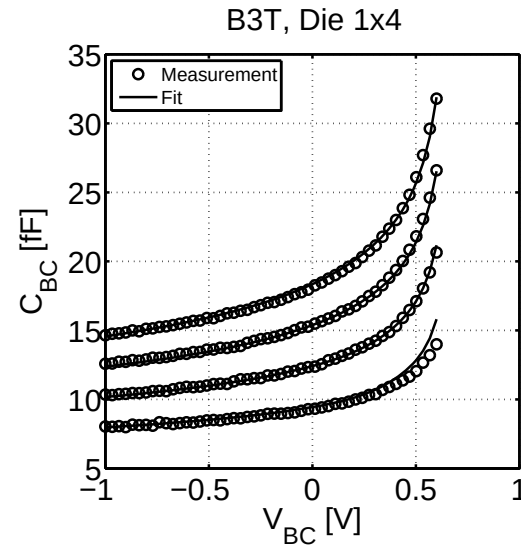
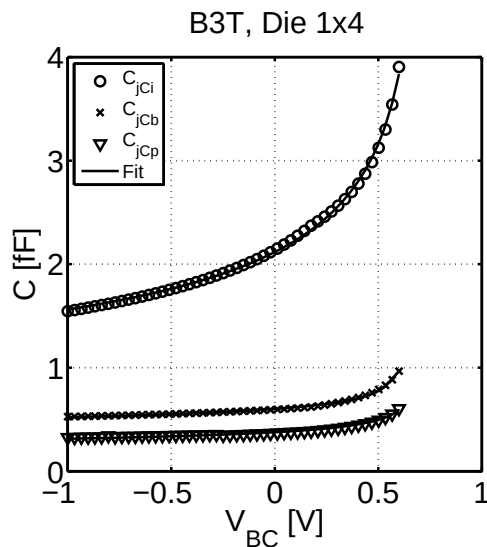
2 Extraction issues w/o regard to model formulation (3)



- XMOD data
- C_{BE} vs. frequency
- $V_{BE} = (-0.6 \dots 0.5)V$
- Estimations of RC-time constants need to be known up-front

2 Extraction issues w/o regard to model formulation (4)

Separation of BC capacitance

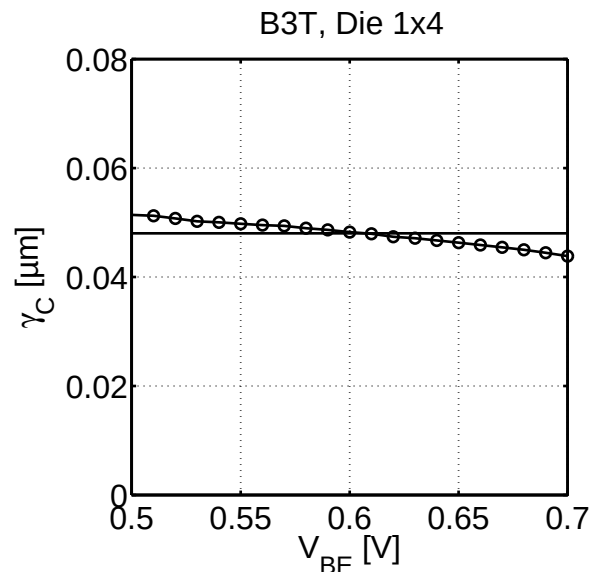


- For proper geometry separation the use of transistor test structures without SIC is desirable.
- Separation here has been done using information from device simulations.

3 Extraction issues w / regard to model formulation

Low current density scaling

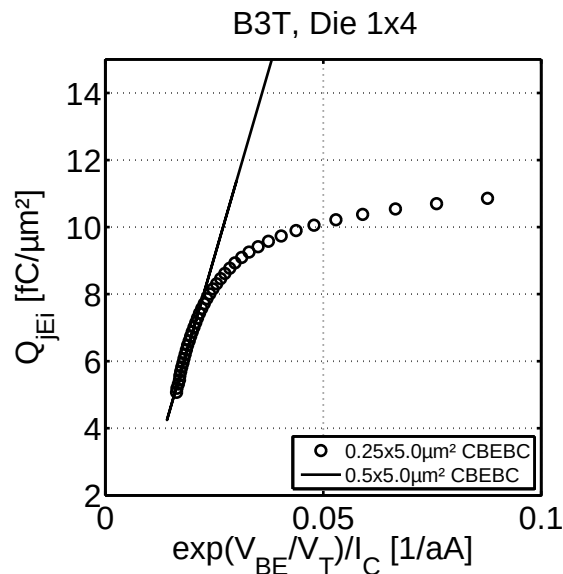
- Decrease of γ_C with V_{BE} , relatively large mean value ($\approx 50\text{nm}$) compared to emitter window and spacer widths



- Physical cause of bias dependence and large value is already under investigation
- Bias dependence rather weak -> use of mean value transitionally sufficient

3 Extraction issues w / regard to model formulation (1)

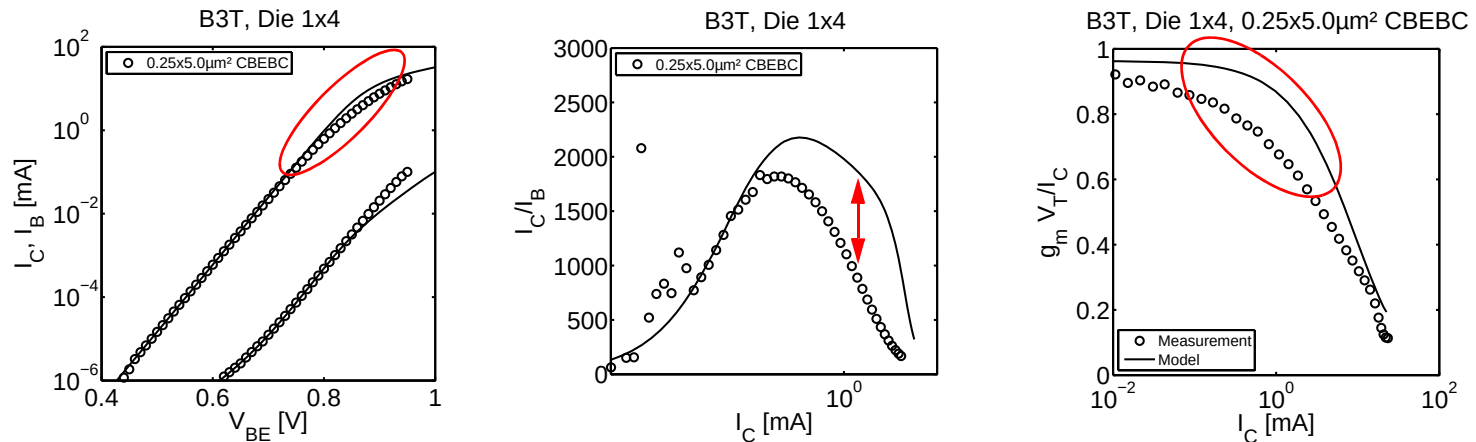
I_T parameter extraction issue



- Standard extraction of Q_{p0} , c_{10} gives negative or too low Q_{p0} values
 - Extracting Q_{p0} from I_C may not give accurate results!
 - Ignoring the bias dependence of h_{jEi} leads to the observed issue
- Refer to presentation of A. Pawlak: extension of the formulation of the transfer current
 - Physics-based solution

3 Extraction issues w / regard to model formulation (2)

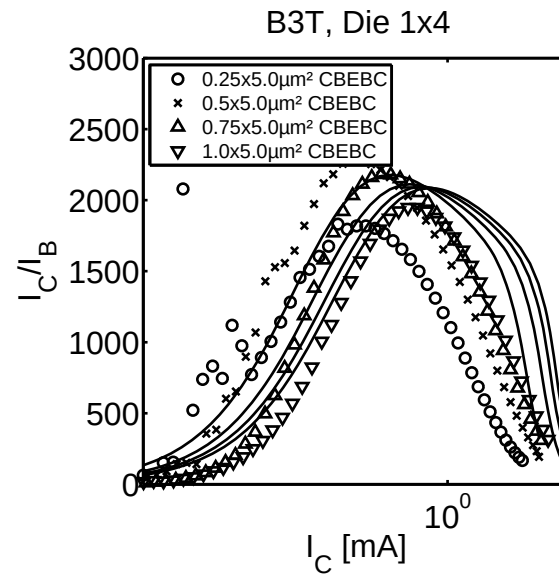
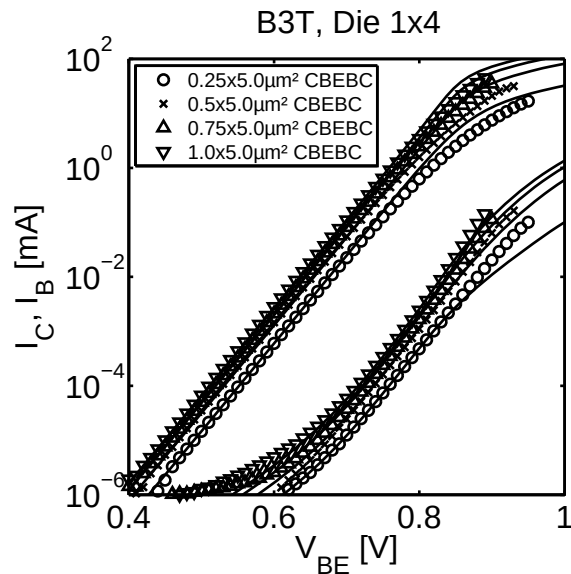
High-current density scaling



- Weighting factors h_{fe} , h_{fc} have no positive impact
- Deviation is enhanced by self-heating effect
- Caused by bias-independent $h_{jei} \rightarrow$ cf. presentation A. Pawlak, "A HICUM extension for medium current densities"

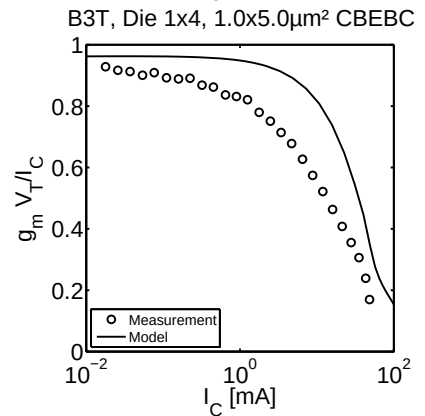
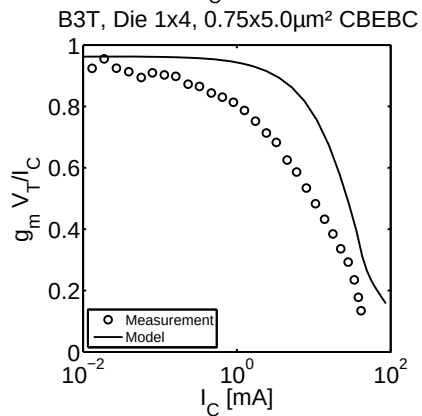
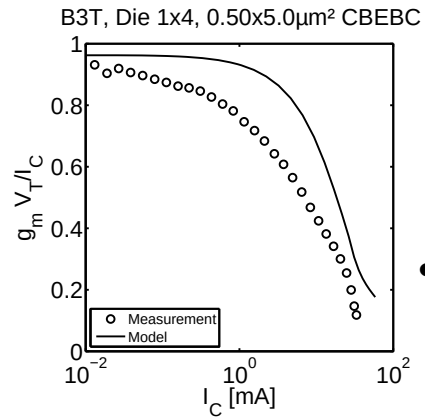
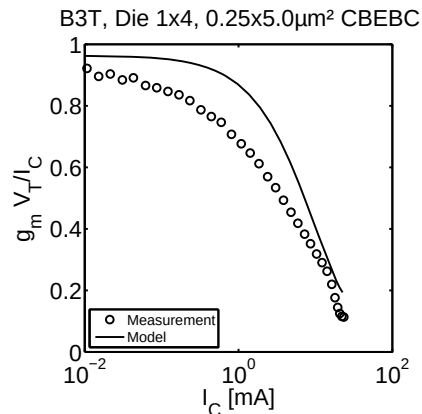
4 Model comparison

Forward gummel plot and DC current gain at $V_{BC} = 0V$



- Expected deviations in high-current region.

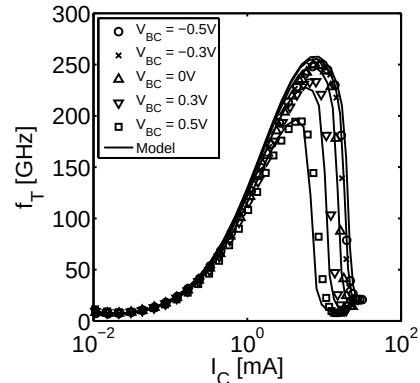
Model comparison (cont'd)



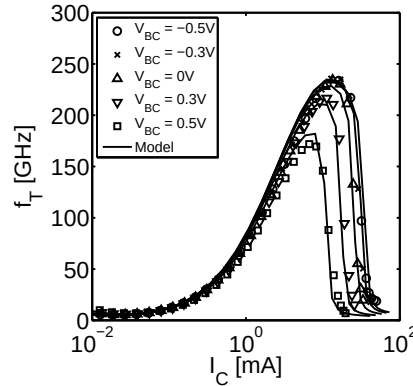
- Normalized transconductance $g_m V_T / I_C$ vs. I_C
- ($g_m \approx \text{Real}\{Y_{21}\}$ @ $f = 1\text{GHz}$)
- $V_{BC} = 0\text{V}$

4 Model comparison (cont'd)

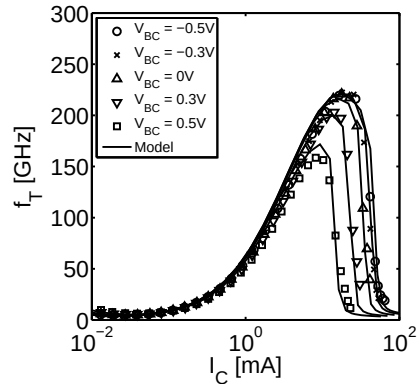
B3T, Die 1x4, 0.25x5.0 μm^2 CBEB



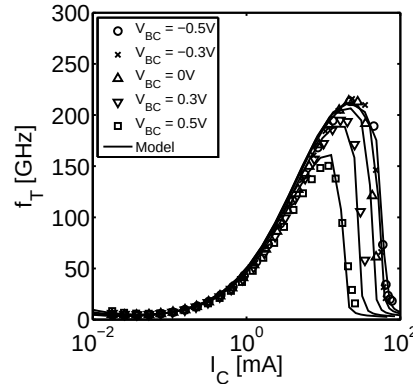
B3T, Die 1x4, 0.50x5.0 μm^2 CBEB



B3T, Die 1x4, 0.75x5.0 μm^2 CBEB

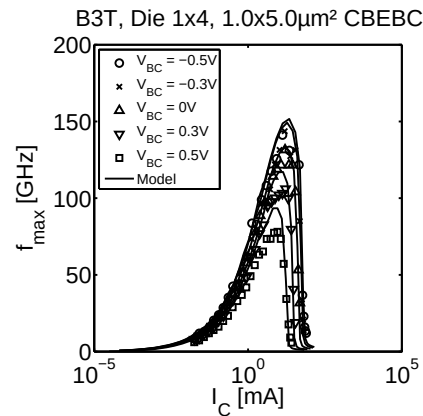
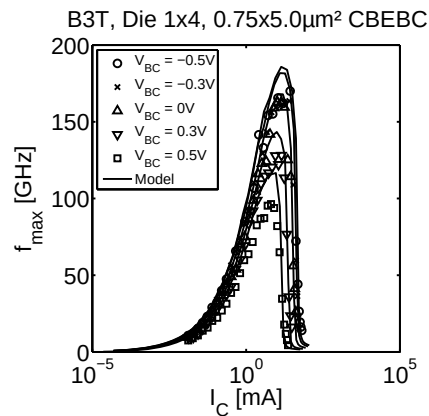
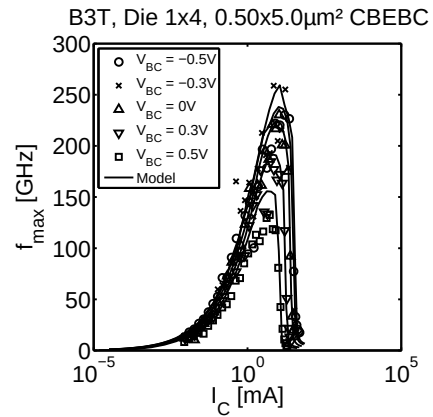
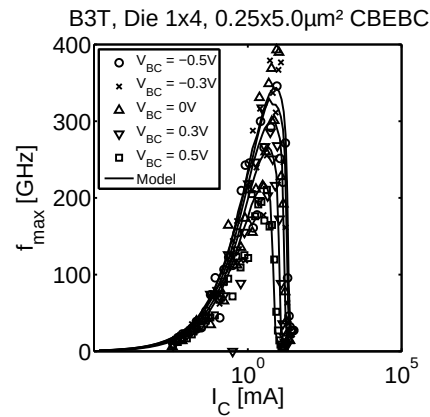


B3T, Die 1x4, 1.0x5.0 μm^2 CBEB



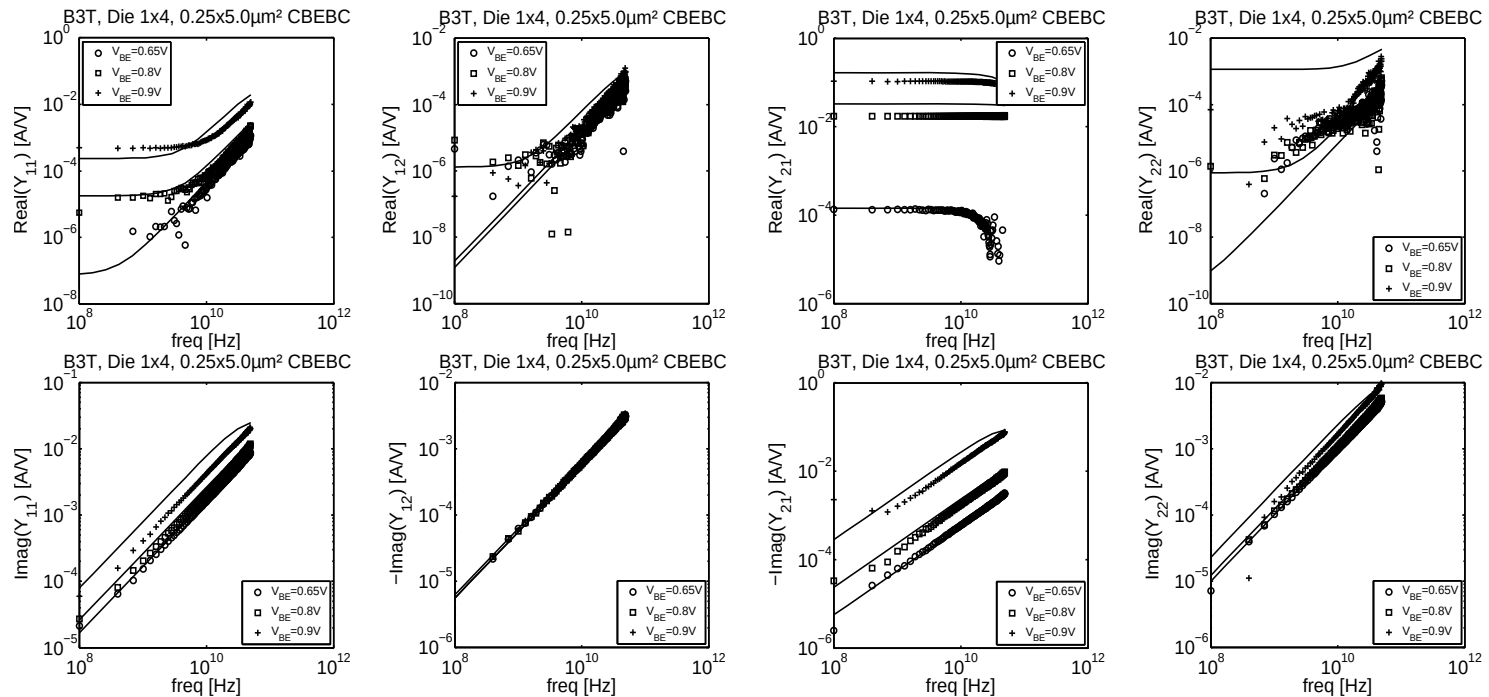
- Transit frequency vs. collector current @ constant $V_{BC} = (-0.5, -0.3, 0.0, 0.3, 0.5)\text{V}$
- Good agreement across bias and several widths.

4 Model comparison (cont'd)



- Maximum oscillation frequency (extrapolated from Mason's unilateral power gain) vs. collector current @ constant V_{BC}
- Sufficient agreement across bias and several widths.

4 Model comparison (cont'd)



- Frequency dependence of Y-parameters for device $0.25 \times 5.0 \mu\text{m}^2$, $V_{BE} = (0.65, 0.8, 0.9)\text{V}$, $V_{BC} = 0\text{V}$.

5 Summary

- Parameter extraction issues could be observed in HICUM/L2 for very advanced HBTs
- Observation of non-standard scaling effects for C_{BE} and I_C
 - Caused by choice of improper frequency range
 - Might be due to emitter dimensions that are not precisely known
- Some issues involve an extension of the model formulation → cf. presentation A. Pawlak

Acknowledgements

This work was supported by:

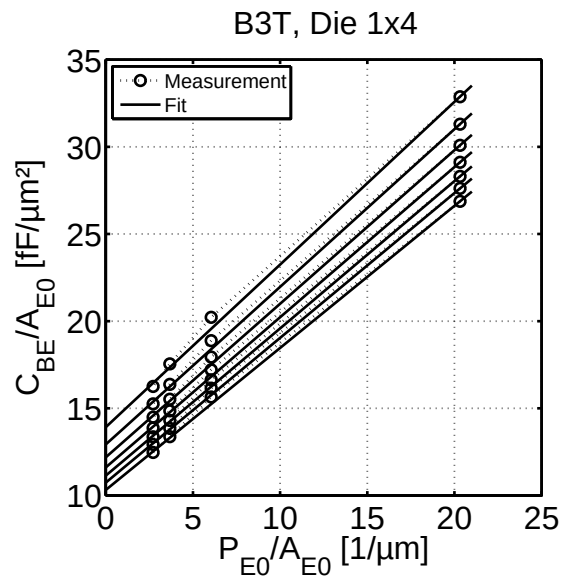
- The European Commision within the framework of the DOTFIVE project (<http://www.dotfive.eu>).

Thanks to:

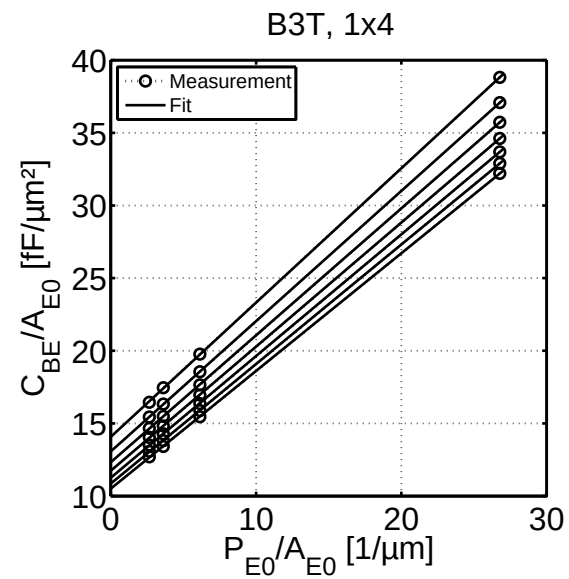
- Bertrand Ardouin for providing model cards and advice
- Didier Céli for his constant support and his help

P/A separation

constant spacer width



optimized spacer widths



Optimization result CBE

	$0.25 \times 5.00 \mu m$	$0.50 \times 5.00 \mu m$	$0.75 \times 5.00 \mu m$	$1.00 \times 5.00 \mu m$
b_{E0}	0.0756	0.3441	0.6127	0.8812
I_{E0}	5.3851	5.0101	4.7516	4.6093
b_s	0.1744	0.1559	0.1373	0.1188
I_s	-0.3851	-0.0101	0.2484	0.3907

Optimization results